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#### What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

#### Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

#### Details

Details	
Product Status	Active
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I <sup>2</sup> C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	31
Program Memory Size	192KB (192K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 10x8/10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	44-LQFP
Supplier Device Package	44-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f100fhafp-50

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

## Table 1-1. List of Ordering Part Numbers

				(1/12)
Pin	Package	Data	Fields of	Ordering Part Number
count		flash	Application Note	
20 pins	20-pin plastic LSSOP	Mounted	А	R5F1006AASP#V0, R5F1006CASP#V0, R5F1006DASP#V0,
	(7.62 mm (300), 0.65			R5F1006EASP#V0
	mm pitch)			R5F1006AASP#X0, R5F1006CASP#X0, R5F1006DASP#X0,
				R5F1006EASP#X0
			D	R5F1006ADSP#V0, R5F1006CDSP#V0, R5F1006DDSP#V0,
				R5F1006EDSP#V0
				R5F1006ADSP#X0, R5F1006CDSP#X0, R5F1006DDSP#X0,
				R5F1006EDSP#X0
			G	R5F1006AGSP#V0, R5F1006CGSP#V0, R5F1006DGSP#V0,
				R5F1006EGSP#V0
				R5F1006AGSP#X0, R5F1006CGSP#X0, R5F1006DGSP#X0,
				R5F1006EGSP#X0
		Not	А	R5F1016AASP#V0, R5F1016CASP#V0, R5F1016DASP#V0,
		mounted		R5F1016EASP#V0
				R5F1016AASP#X0, R5F1016CASP#X0, R5F1016DASP#X0,
				R5F1016EASP#X0
			D	R5F1016ADSP#V0, R5F1016CDSP#V0, R5F1016DDSP#V0,
				R5F1016EDSP#V0
				R5F1016ADSP#X0, R5F1016CDSP#X0, R5F1016DDSP#X0,
				R5F1016EDSP#X0
24 pins	24-pin plastic	Mounted	А	R5F1007AANA#U0, R5F1007CANA#U0, R5F1007DANA#U0,
	HWQFN (4 $ imes$ 4mm,			R5F1007EANA#U0
	0.5 mm pitch)			R5F1007AANA#W0, R5F1007CANA#W0, R5F1007DANA#W0,
				R5F1007EANA#W0
			D	R5F1007ADNA#U0, R5F1007CDNA#U0, R5F1007DDNA#U0,
				R5F1007EDNA#U0
				R5F1007ADNA#W0, R5F1007CDNA#W0, R5F1007DDNA#W0,
				R5F1007EDNA#W0
			G	R5F1007AGNA#U0, R5F1007CGNA#U0, R5F1007DGNA#U0,
				R5F1007EGNA#U0
				R5F1007AGNA#W0, R5F1007CGNA#W0, R5F1007DGNA#W0,
				R5F1007EGNA#W0
		Not	А	R5F1017AANA#U0, R5F1017CANA#U0, R5F1017DANA#U0,
		mounted		R5F1017EANA#U0
				R5F1017AANA#W0, R5F1017CANA#W0, R5F1017DANA#W0,
				R5F1017EANA#W0
			D	R5F1017ADNA#U0, R5F1017CDNA#U0, R5F1017DDNA#U0,
				R5F1017EDNA#U0
				R5F1017ADNA#W0, R5F1017CDNA#W0, R5F1017DDNA#W0,
				R5F1017EDNA#W0

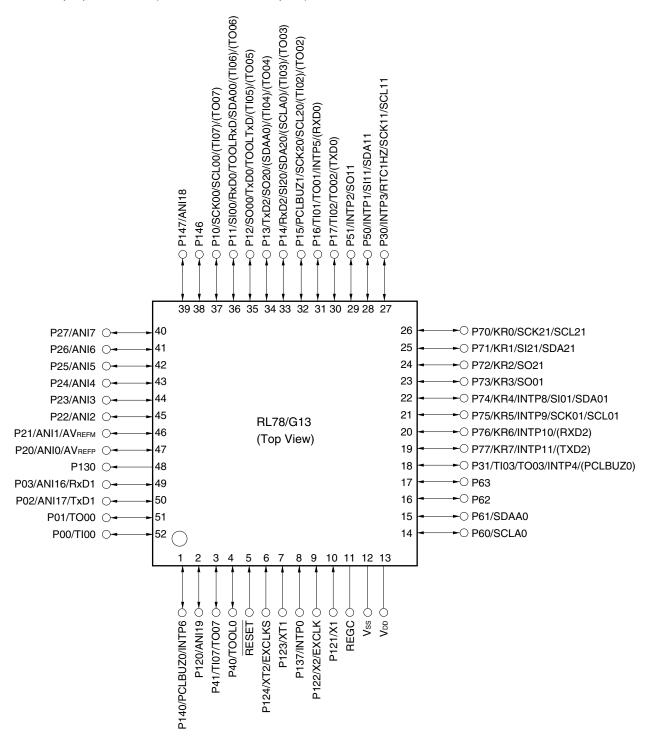
Note For the fields of application, refer to Figure 1-1 Part Number, Memory Size, and Package of RL78/G13.

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.



## 1.3.10 52-pin products

• 52-pin plastic LQFP (10 × 10 mm, 0.65 mm pitch)





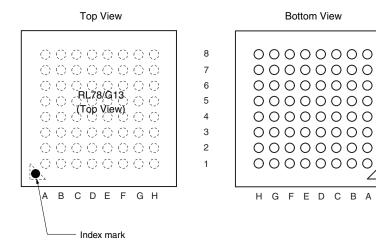
Remarks 1. For pin identification, see 1.4 Pin Identification.

Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). Refer to Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G13 User's Manual.



Bottom View

• 64-pin plastic VFBGA (4 × 4 mm, 0.4 mm pitch)



Pin No.	Name	Pin No.	Name	Pin No.	Name	Pin No.	Name
A1	P05/TI05/TO05	C1	P51/INTP2/SO11	E1	P13/TxD2/SO20/ (SDAA0)/(TI04)/(TO04)	G1	P146
A2	P30/INTP3/RTC1HZ /SCK11/SCL11	C2	P71/KR1/SI21/SDA21	E2	P14/RxD2/SI20/SDA20 /(SCLA0)/(TI03)/(TO03)	G2	P25/ANI5
A3	P70/KR0/SCK21 /SCL21	СЗ	P74/KR4/INTP8/SI01 /SDA01	E3	P15/SCK20/SCL20/ (TI02)/(TO02)	G3	P24/ANI4
A4	P75/KR5/INTP9 /SCK01/SCL01	C4	P52/(INTP10)	E4	P16/TI01/TO01/INTP5 /(SI00)/(RxD0)	G4	P22/ANI2
A5	P77/KR7/INTP11/ (TxD2)	C5	P53/(INTP11)	E5	P03/ANI16/SI10/RxD1 /SDA10	G5	P130
A6	P61/SDAA0	C6	P63	E6	P41/TI07/TO07	G6	P02/ANI17/SO10/TxD1
A7	P60/SCLA0	C7	Vss	E7	RESET	G7	P00/TI00
A8	EVDD0	C8	P121/X1	E8	P137/INTP0	G8	P124/XT2/EXCLKS
B1	P50/INTP1/SI11 /SDA11	D1	P55/(PCLBUZ1)/ (SCK00)	F1	P10/SCK00/SCL00/ (TI07)/(TO07)	H1	P147/ANI18
B2	P72/KR2/SO21	D2	P06/TI06/TO06	F2	P11/SI00/RxD0 /TOOLRxD/SDA00/ (TI06)/(TO06)	H2	P27/ANI7
В3	P73/KR3/SO01	D3	P17/TI02/TO02/ (SO00)/(TxD0)	F3	P12/SO00/TxD0 /TOOLTxD/(INTP5)/ (TI05)/(TO05)	H3	P26/ANI6
B4	P76/KR6/INTP10/ (RxD2)	D4	P54	F4	P21/ANI1/AVREFM	H4	P23/ANI3
B5	P31/TI03/TO03 /INTP4/(PCLBUZ0)	D5	P42/TI04/TO04	F5	P04/SCK10/SCL10	H5	P20/ANI0/AVREFP
B6	P62	D6	P40/TOOL0	F6	P43	H6	P141/PCLBUZ1/INTP7
B7	Vdd	D7	REGC	F7	P01/TO00	H7	P140/PCLBUZ0/INTP6
B8	EVsso	D8	P122/X2/EXCLK	F8	P123/XT1	H8	P120/ANI19

Cautions 1. Make EVsso pin the same potential as Vss pin.

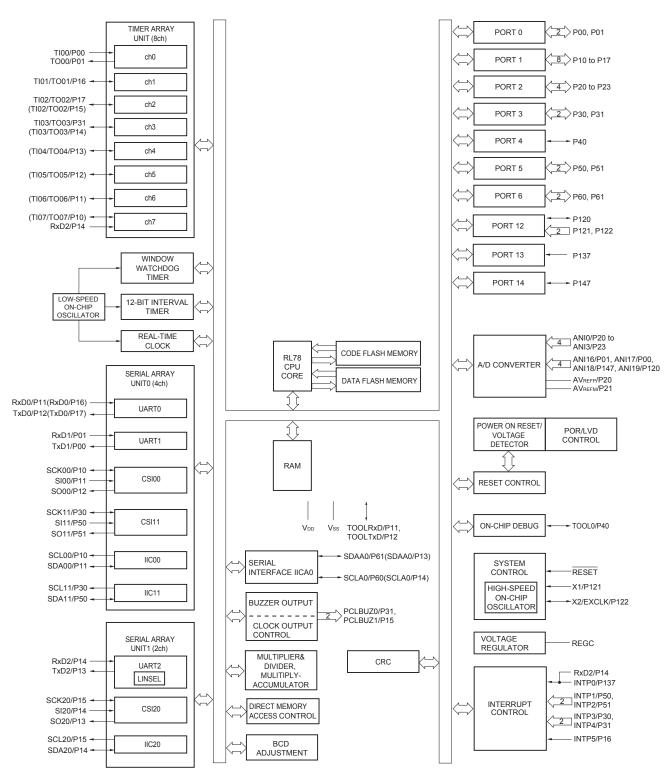
- 2. Make VDD pin the potential that is higher than EVDD0 pin.
- 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

- 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the VDD and EVDD0 pins and connect the Vss and EVss0 pins to separate ground lines.
- 3. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). Refer to Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G13 User's Manual.



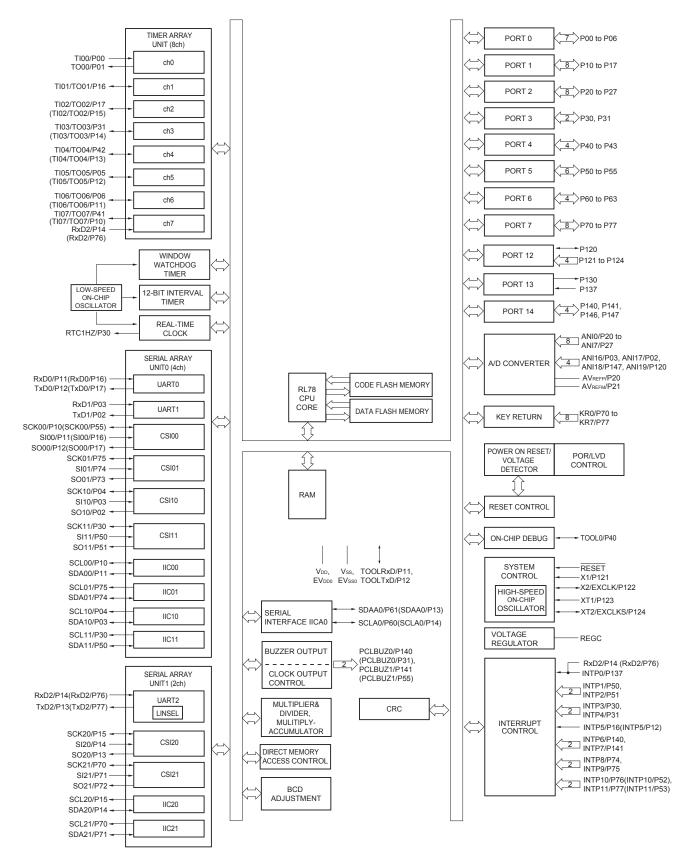
## 1.5.4 30-pin products



**Remark** Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). Refer to Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G13 User's Manual.



## 1.5.11 64-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR). Refer to Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR) in the RL78/G13 User's Manual.



## 2.3.2 Supply current characteristics

## (1) Flash ROM: 16 to 64 KB of 20- to 64-pin products

## $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{\text{SS0}} = 0 \text{ V})$ (1/2)

Parameter	Symbol			Conditions	1	1	MIN.	TYP.	MAX.	Unit
		Operating	HS (high-	f⊪ = 32 MHz <sup>№te 3</sup>	Basic	VDD = 5.0 V		2.1		mA
urrent mode	mode	speed main) mode <sup>Note 5</sup>		operation	$V_{DD} = 3.0 V$		2.1		mA	
			mode		Normal	V <sub>DD</sub> = 5.0 V		4.6	7.0	mA
					operation	$V_{DD} = 3.0 V$		4.6	7.0	mA
					Normal	$V_{DD} = 5.0 V$		3.7	5.5	mA
					operation	$V_{DD} = 3.0 V$		3.7	5.5	mA
				fıн = 16 MHz <sup>№te 3</sup>	Normal	VDD = 5.0 V		2.7	4.0	mA
					operation	V <sub>DD</sub> = 3.0 V		2.7	4.0	mA
			LS (low-	fін = 8 MHz <sup>Note 3</sup>	Normal	VDD = 3.0 V		1.2	1.8	mA
			speed main) mode <sup>Note 5</sup>		operation	V <sub>DD</sub> = 2.0 V		1.2	1.8	mA
			LV (low-	$f_{IH} = 4 \text{ MHz}^{Note 3}$	Normal	V <sub>DD</sub> = 3.0 V		1.2	1.7	mA
			voltage main) mode Note 5		operation	V <sub>DD</sub> = 2.0 V		1.2	1.7	mA
		HS (high-	f <sub>MX</sub> = 20 MHz <sup>Note 2</sup> ,	Normal	Square wave input		3.0	4.6	mA	
		speed main) mode <sup>Note 5</sup>	$V_{DD} = 5.0 V$	operation	Resonator connection		3.2	4.8	mA	
			$f_{MX} = 20 \text{ MHz}^{Note 2},$	Normal	Square wave input		3.0	4.6	mA	
			$V_{DD} = 3.0 V$	operation	Resonator connection		3.2	4.8	mA	
			$f_{MX} = 10 \text{ MHz}^{Note 2},$	Normal	Square wave input		1.9	2.7	mA	
			LS (low- speed main) mode <sup>Note 5</sup>	$V_{DD} = 5.0 V$	operation	Resonator connection		1.9	2.7	mA
				fмx = 10 MHz <sup>Note 2</sup> ,	Normal	Square wave input		1.9	2.7	mA
				$V_{DD} = 3.0 V$	operation	Resonator connection		1.9	2.7	mA
				$f_{MX} = 8 \text{ MHz}^{Note 2},$	Normal	Square wave input		1.1	1.7	mA
				$V_{DD} = 3.0 V$	operation	Resonator connection		1.1	1.7	mA
				f <sub>MX</sub> = 8 MHz <sup>Note 2</sup> ,	Normal	Square wave input		1.1	1.7	mA
				$V_{DD} = 2.0 V$	operation	Resonator connection		1.1	1.7	mA
			Subsystem	fsuв = 32.768 kHz	Normal	Square wave input		4.1	4.9	μA
			clock operation	Note 4 $T_A = -40^{\circ}C$	operation	Resonator connection		4.2	5.0	μA
				fsuв = 32.768 kHz	Normal	Square wave input		4.1	4.9	μA
			<sup>Note 4</sup> T <sub>A</sub> = +25°C	operation	Resonator connection		4.2	5.0	μA	
				fsuв = 32.768 kHz	Normal	Square wave input		4.2	5.5	μA
				Note 4	operation	Resonator		4.3	5.6	μΑ
				T <sub>A</sub> = +50°C		connection				
				fsuв = 32.768 kHz	Normal	Square wave input		4.3	6.3	μA
			Note 4 $T_A = +70^{\circ}C$	operation	Resonator connection		4.4	6.4	μA	
				fsuв = 32.768 kHz	Normal	Square wave input	<u> </u>	4.6	7.7	μA
			Note 4 $T_A = +85^{\circ}C$	operation	Resonator connection		4.7	7.8	μA	

(Notes and Remarks are listed on the next page.)



- **Notes 1.** Total current flowing into V<sub>DD</sub> and EV<sub>DD0</sub>, including the input leakage current flowing when the level of the input pin is fixed to V<sub>DD</sub>, EV<sub>DD0</sub> or V<sub>SS</sub>, EV<sub>SS0</sub>. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. During HALT instruction execution by flash memory.
  - 3. When high-speed on-chip oscillator and subsystem clock are stopped.
  - 4. When high-speed system clock and subsystem clock are stopped.
  - When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the RTC is included. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
  - 6. Not including the current flowing into the RTC, 12-bit interval timer, and watchdog timer.
  - 7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.
    - HS (high-speed main) mode: 2.7 V  $\leq$  V\_{DD}  $\leq$  5.5 V@1 MHz to 32 MHz
      - 2.4 V  $\leq$  V\_{DD}  $\leq$  5.5 V@1 MHz to 16 MHz
    - LS (low-speed main) mode:  $1.8 \text{ V} \le V_{\text{DD}} \le 5.5 \text{ V} @ 1 \text{ MHz}$  to 8 MHz
    - LV (low-voltage main) mode: 1.6 V  $\leq$  V\_{DD}  $\leq$  5.5 V@1 MHz to 4 MHz
  - 8. Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: High-speed on-chip oscillator clock frequency
  - **3.** fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
  - Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is T<sub>A</sub> = 25°C



- **Notes 1.** Total current flowing into Vbb, EVbbb, and EVbb1, including the input leakage current flowing when the level of the input pin is fixed to Vbb, EVbb0, and EVbb1, or Vss, EVsso, and EVss1. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
  - 2. When high-speed on-chip oscillator and subsystem clock are stopped.
  - 3. When high-speed system clock and subsystem clock are stopped.
  - 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the 12-bit interval timer and watchdog timer.
  - **5.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.
    - HS (high-speed main) mode: 2.7 V  $\leq$  V\_{DD}  $\leq$  5.5 V@1 MHz to 32 MHz
      - 2.4 V  $\leq$  V<sub>DD</sub>  $\leq$  5.5 V@1 MHz to 16 MHz
    - LS (low-speed main) mode:  $~~1.8~V \leq V_{\text{DD}} \leq 5.5~V @\,1~\text{MHz}$  to 8 MHz
    - LV (low-voltage main) mode: 1.6 V  $\leq$  V\_DD  $\leq$  5.5 V@1 MHz to 4 MHz
- Remarks 1. fmx: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
  - 2. fin: High-speed on-chip oscillator clock frequency
  - **3.** fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
  - 4. Except subsystem clock operation, temperature condition of the TYP. value is  $T_A = 25^{\circ}C$



## (4) Peripheral Functions (Common to all products)

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ V}_{SS} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$

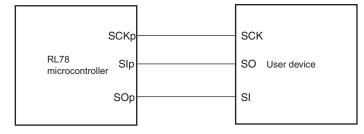
Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Low-speed on- chip oscillator operating current	IFIL <sup>Note 1</sup>				0.20		μA
RTC operating current	RTC Notes 1, 2, 3				0.02		μA
12-bit interval timer operating current	IT <sup>Notes 1, 2, 4</sup>				0.02		μA
Watchdog timer operating current	WDT Notes 1, 2, 5	f⊩ = 15 kHz			0.22		μA
A/D converter	ADC Notes 1, 6	When	Normal mode, $AV_{REFP} = V_{DD} = 5.0 V$		1.3	1.7	mA
operating current		conversion at maximum speed	Low voltage mode, $AV_{REFP} = V_{DD} = 3.0 V$		0.5	0.7	mA
A/D converter reference voltage current	ADREF <sup>Note 1</sup>				75.0		μA
Temperature sensor operating current	ITMPS <sup>Note 1</sup>				75.0		μA
LVD operating current	LVI Notes 1, 7				0.08		μA
Self- programming operating current	IFSP <sup>Notes 1, 9</sup>				2.50	12.20	mA
BGO operating current	BGO Notes 1, 8				2.50	12.20	mA
SNOOZE	ISNOZ Note 1	ADC operation	The mode is performed Note 10		0.50	0.60	mA
operating current			The A/D conversion operations are performed, Low voltage mode, $AV_{REFP} = V_{DD} = 3.0 \text{ V}$		1.20	1.44	mA
		CSI/UART opera	tion		0.70	0.84	mA

Notes 1. Current flowing to  $V_{DD}$ .

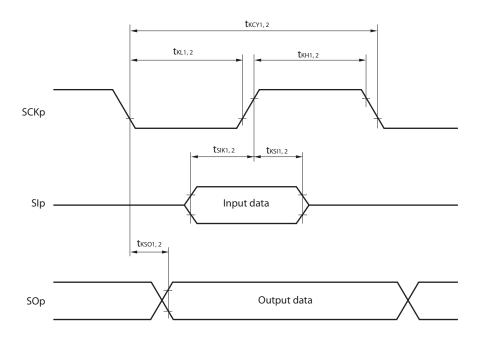
- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- 3. Current flowing only to the real-time clock (RTC) (excluding the operating current of the low-speed onchip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IRTC, when the real-time clock operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added. IDD2 subsystem clock operation includes the operational current of the real-time clock.
- 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and IIT, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- 5. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The supply current of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer is in operation.



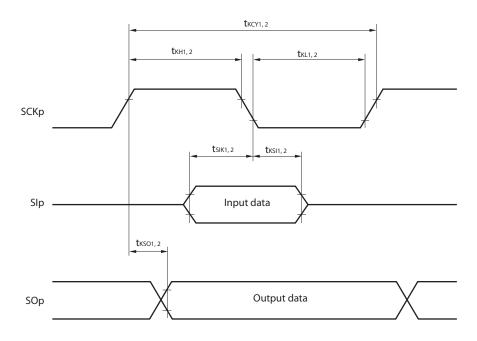
## CSI mode connection diagram (during communication at same potential)

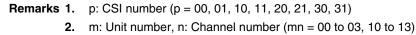


CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



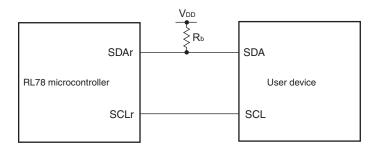
CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



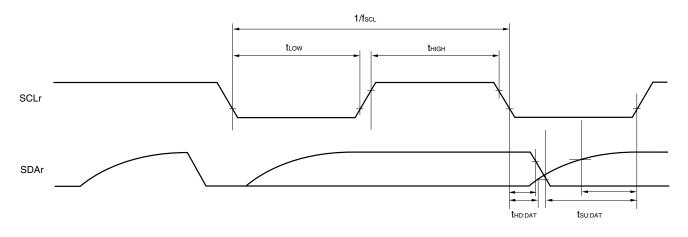




## Simplified I<sup>2</sup>C mode mode connection diagram (during communication at same potential)



## Simplified I<sup>2</sup>C mode serial transfer timing (during communication at same potential)



- **Remarks 1.** R<sub>b</sub>[Ω]:Communication line (SDAr) pull-up resistance, C<sub>b</sub>[F]: Communication line (SDAr, SCLr) load capacitance
  - r: IIC number (r = 00, 01, 10, 11, 20, 21, 30, 31), g: PIM number (g = 0, 1, 4, 5, 8, 14),
    h: POM number (g = 0, 1, 4, 5, 7 to 9, 14)
  - 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1),

n: Channel number (n = 0 to 3), mn = 00 to 03, 10 to 13)



2.6.5 Power supply voltage rising slope characteristics

#### $(T_A = -40 \text{ to } +85^{\circ}C, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD				54	V/ms

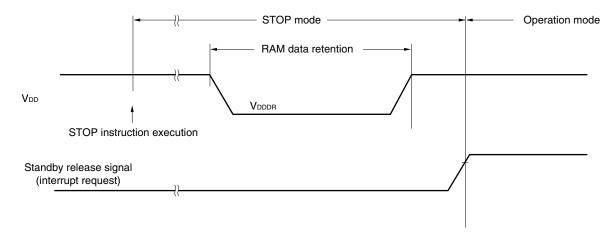
Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until  $V_{DD}$  reaches the operating voltage range shown in 2.4 AC Characteristics.

## 2.7 RAM Data Retention Characteristics

#### $(T_A = -40 \text{ to } +85^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 <sup>Note</sup>		5.5	V

**Note** This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.





#### RL78/G13 3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS TA = -40 to +105°C)

Remark The electrical characteristics of the products G: Industrial applications (T<sub>A</sub> = -40 to +105°C) are different from those of the products "A: Consumer applications, and D: Industrial applications". For details, refer to 3.1 to 3.10.

## 3.1 Absolute Maximum Ratings

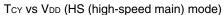
Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	VDD		–0.5 to +6.5	V
	EVDD0, EVDD1	EVDD0 = EVDD1	–0.5 to +6.5	V
	EVsso, EVss1	EVsso = EVss1	–0.5 to +0.3	V
REGC pin input voltage	VIREGC	REGC	$-0.3$ to +2.8 and $-0.3$ to $V_{\text{DD}}$ +0.3 $^{\text{Note 1}}$	V
Input voltage	VI1	P00 to P07, P10 to P17, P30 to P37, P40 to P47,	-0.3 to EV <sub>DD0</sub> +0.3	V
		P50 to P57, P64 to P67, P70 to P77, P80 to P87, P90 to P97, P100 to P106, P110 to P117, P120, P125 to P127, P140 to P147	and –0.3 to $V_{DD}$ +0.3 <sup>Note 2</sup>	
	V <sub>I2</sub>	P60 to P63 (N-ch open-drain)	-0.3 to +6.5	V
	Vı3	P20 to P27, P121 to P124, P137, P150 to P156, EXCLK, EXCLKS, RESET	-0.3 to V <sub>DD</sub> +0.3 <sup>Note 2</sup>	V
Output voltage	Voi	P00 to P07, P10 to P17, P30 to P37, P40 to P47, P50 to P57, P60 to P67, P70 to P77, P80 to P87, P90 to P97, P100 to P106, P110 to P117, P120, P125 to P127, P130, P140 to P147		V
	V <sub>02</sub>	P20 to P27, P150 to P156	-0.3 to V <sub>DD</sub> +0.3 <sup>Note 2</sup>	V
Analog input voltage	VAI1	ANI16 to ANI26	$-0.3$ to EV_DD0 +0.3 and $-0.3$ to AV_{REF}(+) +0.3 $^{\text{Notes 2, 3}}$	V
	Vai2	ANI0 to ANI14	$-0.3$ to V_DD +0.3 and $-0.3$ to AV_{REF}(+) +0.3^{Notes 2,3}	V

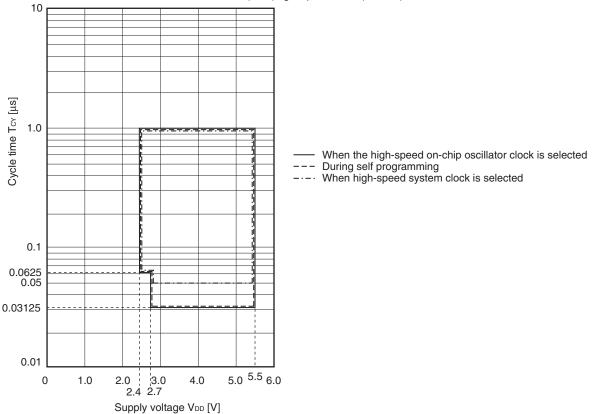
## Absolute Maximum Ratings (T<sub>A</sub> = 25°C) (1/2)

- **Notes 1.** Connect the REGC pin to Vss via a capacitor (0.47 to 1  $\mu$ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.
  - 2. Must be 6.5 V or lower.
  - **3.** Do not exceed AVREF(+) + 0.3 V in case of A/D conversion target pin.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
  - **2.**  $AV_{REF}(+)$  : + side reference voltage of the A/D converter.
  - **3.** Vss : Reference voltage

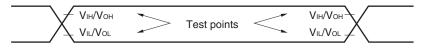


## Minimum Instruction Execution Time during Main System Clock Operation

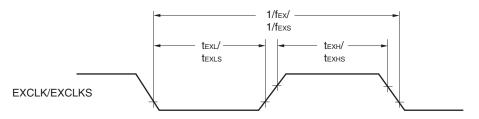




#### **AC Timing Test Points**



## External System Clock Timing





# (7) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (slave mode, SCKp... external clock input)

Parameter	Symbol	0	Conditions	HS (high-spee	HS (high-speed main) Mode		
				MIN.	MAX.		
SCKp cycle time Note 1	<b>t</b> ксү2	$4.0~V \leq EV_{\text{DD0}} \leq 5.5$	24 MHz < fмск	<b>28/f</b> мск		ns	
		V,	$20 \text{ MHz} < f_{MCK} \le 24 \text{ MHz}$	<b>24/f</b> мск		ns	
		$2.7 \: V {\le} V_b {\le} 4.0 \: V$	8 MHz < fмск ≤ 20 MHz	<b>20/f</b> мск		ns	
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	<b>16/f</b> мск		ns	
			fмск $\leq$ 4 MHz	<b>12/f</b> мск		ns	
		$2.7~V \leq EV_{DD0} < 4.0$	24 MHz < fмск	<b>40/f</b> мск		ns	
		V,	$20 \text{ MHz} < f_{\text{MCK}} \le 24 \text{ MHz}$	<b>32/f</b> мск		ns	
		$2.3V{\leq}V_b{\leq}2.7V$	$16 \text{ MHz} < f_{MCK} \le 20 \text{ MHz}$	<b>28/f</b> мск		ns	
			$8 \text{ MHz} < f_{\text{MCK}} \le 16 \text{ MHz}$	24/fмск		ns	
			$4 \text{ MHz} < f_{\text{MCK}} \le 8 \text{ MHz}$	<b>16/f</b> мск		ns	
			fмск $\leq$ 4 MHz	12/fмск		ns	
		$2.4~V \leq EV_{\text{DD0}} < 3.3$	24 MHz < fмск	<b>96/f</b> мск		ns	
		V,	$20 \text{ MHz} < f_{MCK} \le 24 \text{ MHz}$	<b>72/f</b> мск		ns	
		$1.6V \le V_b \le 2.0V$	$16 \text{ MHz} < f_{\text{MCK}} \le 20 \text{ MHz}$	<b>64/f</b> мск		ns	
			$8 \text{ MHz} < f_{\text{MCK}} \le 16 \text{ MHz}$	<b>52/f</b> мск		ns	
			4 MHz < fмск ≤ 8 MHz	<b>32/</b> fмск		ns	
			fмск $\leq$ 4 MHz	20/fмск		ns	
SCKp high-/low-level width	tкн2, tкL2	$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD0}} \leq 5. \\ 2.7 \ V \leq V_b \leq 4.0 \ V \end{array}$		tkcy2/2 - 24		ns	
		$\begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} < 4. \\ 2.3 \ V \leq V_{b} \leq 2.7 \ V \end{array}$		tkcy2/2 - 36		ns	
		$\begin{array}{l} 2.4 \; V \leq EV_{\text{DD0}} < 3. \\ 1.6 \; V \leq V_{\text{b}} \leq 2.0 \; V \end{array}$		tkcy2/2 - 100		ns	
SIp setup time (to SCKp↑) <sup>Note2</sup>	tsik2	$\begin{array}{l} 4.0 \; V \leq EV_{\text{DD0}} \leq 5. \\ 2.7 \; V \leq V_b \leq 4.0 \; V \end{array}$		1/fмск + 40		ns	
		$\begin{array}{l} 2.7 \ V \leq EV_{DD0} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V \end{array}$		1/fмск + 40		ns	
		$\label{eq:states} \begin{array}{l} 2.4 \ V \leq EV_{\text{DD0}} < 3. \\ 1.6 \ V \leq V_{\text{b}} \leq 2.0 \ V \end{array}$		1/fмск + 60		ns	
SIp hold time (from SCKp↑) <sup>№te 3</sup>	tksi2			1/fмск + 62		ns	
Delay time from SCKp↓ to SOp output <sup>№te 4</sup>	tkso2	$\begin{array}{l} 4.0 \ V \leq EV_{\text{DD0}} \leq 5. \\ C_{\text{b}} = 30 \ p\text{F}, \ R_{\text{b}} = 1 \end{array}$	5 V, 2.7 V $\leq$ Vb $\leq$ 4.0 V, .4 k\Omega		2/fмск + 240	ns	
		$\label{eq:constraint} \begin{array}{l} 2.7 \ V \leq EV_{\text{DD0}} < 4. \\ C_{\text{b}} = 30 \ \text{pF}, \ R_{\text{b}} = 2 \end{array}$	0 V, 2.3 V $\leq$ V <sub>b</sub> $\leq$ 2.7 V, 2.7 kΩ		2/fмск + 428	ns	
			3 V, 1.6 V $\leq$ Vb $\leq$ 2.0 V		2/fмск + 1146	ns	

(Notes, Caution and Remarks are listed on the next page.)



(2) When reference voltage (+) = AV<sub>REFP</sub>/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AV<sub>REFM</sub>/ANI1 (ADREFM = 1), target pin : ANI16 to ANI26

 $(T_{A} = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{\text{DD0}} = \text{EV}_{\text{DD1}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, 2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{V}_{\text{SS}} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V},$ Reference voltage (+) = AV\_{\text{REFP}}, Reference voltage (-) = AV\_{\text{REFM}} = 0 \text{ V})

Parameter	Symbol	Conditior	าร	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error <sup>Note 1</sup>	AINL	$\begin{array}{l} 10\text{-bit resolution} \\ EV_{DD0} \leq AV_{\text{REFP}} = V_{\text{DD}}  ^{\text{Notes 3, 4}} \end{array}$	$\begin{array}{l} 2.4 \ V \leq AV_{REFP} \leq 5.5 \\ V \end{array}$		1.2	±5.0	LSB
Conversion time	<b>t</b> CONV	10-bit resolution	$3.6~V \leq V \text{DD} \leq 5.5~V$	2.125		39	μs
		Target pin : ANI16 to ANI26	$2.7~V \leq V \text{DD} \leq 5.5~V$	3.1875		39	μs
			$2.4~V \leq V \text{DD} \leq 5.5~V$	17		39	μs
Zero-scale error <sup>Notes 1, 2</sup>	Ezs	$\begin{array}{l} \mbox{10-bit resolution} \\ \mbox{EVDD0} \leq AV_{\text{REFP}} = V_{\text{DD}} ^{\text{Notes 3, 4}} \end{array}$	$\begin{array}{l} 2.4 \ V \leq AV_{\text{REFP}} \leq 5.5 \\ V \end{array}$			±0.35	%FSR
Full-scale error <sup>Notes 1, 2</sup>	Efs	$\begin{array}{l} \text{10-bit resolution} \\ \text{EVDD0} \leq AV_{\text{REFP}} = V_{\text{DD}} \\ \end{array} \end{array}$	$\begin{array}{l} 2.4 \ V \leq AV_{\text{REFP}} \leq 5.5 \\ V \end{array}$			±0.35	%FSR
Integral linearity error <sup>Note 1</sup>	ILE	10-bit resolution $EV \text{DD0} \leq AV_{\text{REFP}} = V_{\text{DD}}^{\text{Notes 3, 4}}$	$\begin{array}{l} 2.4 \ V \leq AV_{\text{REFP}} \leq 5.5 \\ V \end{array}$			±3.5	LSB
Differential linearity error	DLE	$\begin{array}{l} 10\text{-bit resolution} \\ EV \text{DD0} \leq AV_{\text{REFP}} = V_{\text{DD}}  ^{\text{Notes 3, 4}} \end{array}$	$\begin{array}{l} 2.4 \ V \leq AV_{\text{REFP}} \leq 5.5 \\ V \end{array}$			±2.0	LSB
Analog input voltage	Vain	ANI16 to ANI26		0		AVREFP and EVDD0	V

**Notes 1.** Excludes quantization error ( $\pm 1/2$  LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- When AV<sub>REFP</sub> < V<sub>DD</sub>, the MAX. values are as follows. Overall error: Add ±1.0 LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>. Zero-scale error/Full-scale error: Add ±0.05%FSR to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>. Integral linearity error/ Differential linearity error: Add ±0.5 LSB to the MAX. value when AV<sub>REFP</sub> = V<sub>DD</sub>.
   When AV<sub>REFP</sub> < EV<sub>DD0</sub> ≤ V<sub>DD</sub>, the MAX. values are as follows.
- 4. When AVREFP < EVDDD S VDD, the MAX. values are as follows. Overall error: Add ±4.0 LSB to the MAX. value when AVREFP = VDD. Zero-scale error/Full-scale error: Add ±0.20%FSR to the MAX. value when AVREFP = VDD. Integral linearity error/ Differential linearity error: Add ±2.0 LSB to the MAX. value when AVREFP = VDD.



## 4.9 48-pin Products

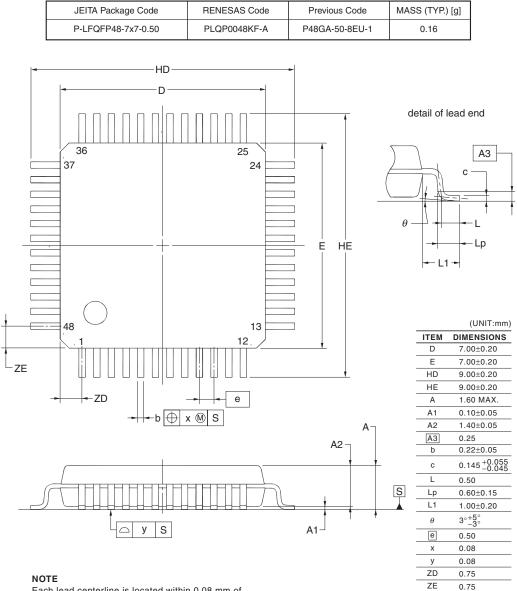
R5F100GAAFB, R5F100GCAFB, R5F100GDAFB, R5F100GEAFB, R5F100GFAFB, R5F100GGAFB, R5F100GHAFB, R5F100GJAFB, R5F100GLAFB

R5F101GAAFB, R5F101GCAFB, R5F101GDAFB, R5F101GEAFB, R5F101GFAFB, R5F101GGAFB, R5F101GHAFB, R5F101GJAFB, R5F101GKAFB, R5F101GLAFB

R5F100GADFB, R5F100GCDFB, R5F100GDDFB, R5F100GEDFB, R5F100GFDFB, R5F100GGDFB, R5F100GHDFB, R5F100GJDFB, R5F100GKDFB, R5F100GLDFB

R5F101GADFB, R5F101GCDFB, R5F101GDDFB, R5F101GEDFB, R5F101GFDFB, R5F101GGDFB, R5F101GHDFB, R5F101GJDFB, R5F101GKDFB, R5F101GLDFB

R5F100GAGFB, R5F100GCGFB, R5F100GDGFB, R5F100GEGFB, R5F100GFGFB, R5F100GGGFB, R5F100GHGFB, R5F100GJGFB



Each lead centerline is located within 0.08 mm of its true position at maximum material condition.

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Rev.			Description
	Date	Page	Summary
3.00	Aug 02, 2013	81	Modification of figure of AC Timing Test Points
		81	Modification of description and note 3 in (1) During communication at same potential (UART mode)
		83	Modification of description in (2) During communication at same potential (CSI mode)
		84	Modification of description in (3) During communication at same potential (CSI mode)
		85	Modification of description in (4) During communication at same potential (CSI mode) (1/2)
		86	Modification of description in (4) During communication at same potential (CSI mode) (2/2)
		88	Modification of table in (5) During communication at same potential (simplified I <sup>2</sup> C mode) (1/2)
		89	Modification of table and caution in (5) During communication at same potential (simplified I <sup>2</sup> C mode) (2/2)
		91	Modification of table and notes 1 and 4 in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (1/2)
		92, 93	Modification of table and notes 2 to 7 in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (2/2)
		94	Modification of remarks 1 to 4 in (6) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (2/2)
		95	Modification of table in (7) Communication at different potential (2.5 V, 3 V) (CSI mode) (1/2)
		96	Modification of table and caution in (7) Communication at different potential (2.5 V, 3 V) (CSI mode) (2/2)
		97	Modification of table in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (1/3)
		98	Modification of table, note 1, and caution in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (2/3)
		99	Modification of table, note 1, and caution in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (3/3)
		100	Modification of remarks 3 and 4 in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (3/3)
		102	Modification of table in (9) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (1/2)
		103	Modification of table and caution in (9) Communication at different potential (1.8 V, 2.5 V, 3 V) (CSI mode) (2/2)
		106	Modification of table in (10) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified $I^2C$ mode) (1/2)
		107	Modification of table, note 1, and caution in (10) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I <sup>2</sup> C mode) (2/2)
		109	Addition of (1) I <sup>2</sup> C standard mode
		111	Addition of (2) I <sup>2</sup> C fast mode
		112	Addition of (3) I <sup>2</sup> C fast mode plus
		112	Modification of IICA serial transfer timing
		113	Addition of table in 2.6.1 A/D converter characteristics
		113	Modification of description in 2.6.1 (1)
		114	Modification of notes 3 to 5 in 2.6.1 (1)
		115	Modification of description and notes 2, 4, and 5 in 2.6.1 (2)
		116	Modification of description and notes 3 and 4 in 2.6.1 (3)
		117	Modification of description and notes 3 and 4 in 2.6.1 (4)

Rev.	Date	Description	
		Page	Summary
3.00	Aug 02, 2013	163	Modification of table in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified $I^2C$ mode) (1/2)
		164, 165	Modification of table, note 1, and caution in (8) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I <sup>2</sup> C mode) (2/2)
		166	Modification of table in 3.5.2 Serial interface IICA
		166	Modification of IICA serial transfer timing
		167	Addition of table in 3.6.1 A/D converter characteristics
		167, 168	Modification of table and notes 3 and 4 in 3.6.1 (1)
		169	Modification of description in 3.6.1 (2)
		170	Modification of description and note 3 in 3.6.1 (3)
		171	Modification of description and notes 3 and 4 in 3.6.1 (4)
		172	Modification of table and note in 3.6.3 POR circuit characteristics
		173	Modification of table of LVD Detection Voltage of Interrupt & Reset Mode
		173	Modification from Supply Voltage Rise Time to 3.6.5 Power supply voltage rising slope characteristics
		174	Modification of 3.9 Dedicated Flash Memory Programmer Communication (UART)
		175	Modification of table, figure, and remark in 3.10 Timing Specs for Switching Flash Memory Programming Modes
3.10	Nov 15, 2013	123	Caution 4 added.
		125	Note for operating ambient temperature in 3.1 Absolute Maximum Ratings deleted.
3.30	Mar 31, 2016		Modification of the position of the index mark in 25-pin plastic WFLGA ( $3 \times 3$ mm, 0.50 mm pitch) of 1.3.3 25-pin products
			Modification of power supply voltage in 1.6 Outline of Functions [20-pin, 24- pin, 25-pin, 30-pin, 32-pin, 36-pin products]
			Modification of power supply voltage in 1.6 Outline of Functions [40-pin, 44- pin, 48-pin, 52-pin, 64-pin products]
			Modification of power supply voltage in 1.6 Outline of Functions [80-pin, 100- pin, 128-pin products]
			ACK corrected to ACK
			ACK corrected to ACK

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#### NOTES FOR CMOS DEVICES

- (1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN: Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between VIL (MAX) and VIH (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between VIL (MAX) and VIH (MIN).
- (2) HANDLING OF UNUSED INPUT PINS: Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.
- (3) PRECAUTION AGAINST ESD: A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.
- (4) STATUS BEFORE INITIALIZATION: Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.
- (5) POWER ON/OFF SEQUENCE: In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.
- (6) INPUT OF SIGNAL DURING POWER OFF STATE : Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.